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Data Sheet

August 15, 2026

AGILENT / KEYSIGHT

Agilent/Keysight 4062

HP Agilent 4062 Semiconductor Parametric Test System The HP 4062 (4062A) is a semiconductor parametric test system for wafer-level DC and capacitance measurements. OEM HP Journal June 1984 describes the 4141A DC Source/Monitor and 4280A 1 MHz C-Meter/C-V Plotter as the measurement subsystems (nine instrumentation ports total) multiplexed by the 4085A Switching Matrix onto 48 measurement pins. The 4084A Switching Matrix Controller translates HP-IB relay commands and powers 4085A relays. The 4062A system controller also commands the wafer prober over HP-IB. The HP 4062 (4062A) is a semiconductor parametric test system for wafer-level DC and capacitance measurements. OEM HP Journal June 1984 describes the 4141A DC Source/Monitor and 4280A 1 MHz C-Meter/C-V Plotter as the measurement subsystems (nine instrumentation ports total) multiplexed by the 4085A Switching Matrix onto 48 measurement pins. The 4084A Switching Matrix Controller translates HP-IB relay commands and powers 4085A relays. The 4062A system controller also commands the wafer prober over HP-IB. Wafer-process DC parametric and 1 MHz C-V characterization on up to 48 pins.



MODEL

**Agilent / Keysight
4062**

CALIBRATION

**Available on
request**

CONDITION

Used

STATUS

In stock

RFQ / SKU

4062

LISTING

<https://aumictechlabs.com/products/4062-2/>

NIST-traceable cal

SAM registered

30-day returns

NAICS 423690 · 811210 · 541380

This unit

The Agilent/Keysight 4062 is a semiconductor parametric test system engineered for process monitoring and device characterization in integrated circuit manufacturing. This platform delivers

high-precision DC measurements across current, voltage, capacitance, conductance, and pulse force parameters, supported by an intelligent switching matrix capable of accessing up to 96 measurement pins. The system executes spot, sweep, pulse, pulse sweep, and analog search measurement modes with frequency capability to 500 kHz and precision to 0.05%. Technical Specifications Measurement Parameters: DC current, DC voltage, capacitance, conductance, pulse force DC Measurement Modes: Spot, sweep, pulse, pulse sweep, analog search Frequency Range: Up to 500 kHz Measurement Precision: Up to 0.05% Source/Monitor Unit (SMU) Current Range: ± 20 fA to ± 1 A (standard); 2 pA to ± 1 A (Kelvin configuration) Source/Monitor Unit (SMU) Voltage Range: ± 40 μ V to ± 200 V (standard); ± 40 μ V to ± 200 V (Kelvin configuration) Voltage/Voltage-Measurement Unit (VS/VMU) Output Range: ± 1 mV to ± 40 V VS/VMU Measurement Range: ± 40 μ V to ± 40 V; ± 4 μ V to ± 2 V (differential mode) Switching Matrix: Up to 96 measurement pins with 17 instrument ports (all ports access all pins) Source/Monitor Units: 1 high-resolution SMU, 1 high-current SMU (Kelvin), 2 Kelvin SMUs, 1 ground unit (Kelvin) Auxiliary Voltage Ports: 4 ports Connect-Force-Measure Sequence: Typical resistance measurement completes in less than 17 ms Key Features HP BASIC/UX operating environment with HP-UX (System V UNIX) platform Interactive Measurement and Analysis (IMA) Software with softpanel interface for interactive parametric testing SPECS and SPECS-FA software compatibility Configurable pin card options (48 or 96 pins via HP 4085A/B or HP 4089A switching matrices) Data acquisition across multiple test points with flexible instrument port allocation Typical Applications Process monitoring in semiconductor manufacturing Device characterization and parametric testing Integrated circuit development and yield optimization Compatibility & Integration Available in HP 4062C, HP 4062UX, and HP 4062F configurations. Supports standard networking for remote operation. Compatible with auxiliary instrumentation such as LCR meters (e.g., HP 4284A, 20 Hz–1 MHz).

4062 Characteristics / Specifications

PARAMETER	VALUE
Model	4062
Related Model	4062A
Instrument Type	Semiconductor parametric test system
Pin Count	48 measurement pins
Dc Subsystem	4141A DC Source/Monitor
Capacitance Subsystem	4280A 1 MHzCMeter / C-V Plotter
Instrumentation Ports	nine instrumentation ports total
Switching Matrix	4085A Switching Matrix
Matrix Controller	4084A Switching Matrix Controller
System Bus	HP-IB (IEEE-488)
Prober Control	wafer prober controlled via HP-IB
Measurement Classes	DC current/voltage and AC capacitance/conductance
Manufacturer	HP Agilent Keysight
Use Case	wafer parametric test
Literature	Hewlett-Packard Journal June 1984 4062A semiconductor parametric test system
Family	HP 4062A parametric test
Documentation Type	OEM HP Journal 4062A architecture
Brand Lineage	Hewlett Packard Agilent Keysight
System Role	parametric test main system
Form Factor	racked parametric test system
Related Controller	4062A system controller
Year Class	1984 4062A family
Switching Path	4084A plus 4085A matrix subsystem
Low Current Design	4085A designed for low-current and capacitance measurements

4062 Specifications

PARAMETER	VALUE
HP Agilent 4062 Semiconductor Parametric Test System	Overview
Applications	Wafer-process DC parametric and 1 MHz C-V characterization on up to 48 pins.
Key Features	48 measurement pins
Technical Specifications	Model: 4062

Full OEM specifications

Complete technical content extracted from the manufacturer datasheet. Sparse OEM tables are reconstructed as tables below; other text is preserved as paragraphs.

Specifications	
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Model	4062
Related Model	4062A
Instrument Type	Semiconductor parametric test system
Pin Count	48 measurement pins
Dc Subsystem	4141A DC Source/Monitor
Capacitance Subsystem	4280A 1 MHzCMeter / C-V Plotter
Instrumentation Ports	nine instrumentation ports total
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System Bus	HP-IB (IEEE-488)
Prober Control	wafer prober controlled via HP-IB
Measurement Classes	DC current/voltage and AC capacitance/conductance
Manufacturer	HP Agilent Keysight
Use Case	wafer parametric test
Literature	Hewlett-Packard Journal June 1984 4062A semiconductor parametric test system
Family	HP 4062A parametric test
Documentation Type	OEM HP Journal 4062A architecture
Brand Lineage	Hewlett Packard Agilent Keysight
System Role	parametric test main system
Form Factor	racked parametric test system
Related Controller	4062A system controller
Year Class	1984 4062A family
Switching Path	4084A plus 4085A matrix subsystem
Low Current Design	4085A designed for low-current and capacitance measurements
Notes	
From Hewlett-Packard Journal June 1984 4062A architecture (48 pins, 4141A, 4280A, nine ports, 4085A/4084A,	

HP-IB prober). Current ranges, capacitance accuracy, and pin leakage are on the 4062A/4141A/4280A/4085A specification sheets.

Available from Aumictech

Used and refurbished unit evaluated in-house. Calibration: Available on request. Used · In stock.

Request a quote: sales@aumictech.com · +1 (484) 841-9341

Aumictech

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Technical content from manufacturer specifications. Unit photo/stock from Aumictech listing when available. Specifications subject to OEM documentation and unit condition.